

BNQ 1922-900/2020

Masks Intended for Working Environments — Attestation Document



CONTENTS

		Page		
	INTRODUCTION			
1	PURPOSE AND SCOPE			
2	NORMATIVE REFERENCES			
	2.1 GENERAL2.2 DOCUMENTS FROM STANDARDS BODIES2.3 OTHER DOCUMENT	3 3 4		
3	DEFINITIONS			
4	GENERAL REQUIREMENTS OF THE CONFORMITY ATTESTATION PROGRAM			
5	GENERAL REQUIREMENTS RELATING TO THE MASK			
6	SPECIFIC REQUIREMENTS RELATING TO THE MASK AND TEST METHODS			
7	SAMPLING FOR ATTESTATION			
8	MARKING			
9	REQUIREMENTS RELATING TO THE QUALITY MANAGEMENT SYSTEM			
10	RULES OF PROCEDURE FOR CONFORMITY ATTESTATION			
	 10.1 GENERAL 10.2 APPLICATION FOR CONFORMITY ATTESTATION 10.3 EXAMINATION OF THE ENTERPRISE'S DOCUMENTS 10.4 INSPECTION VISIT FOR SAMPLING PURPOSES 10.5 DECISION ON ATTESTATION AND ISSUING OF THE ATTESTATION LE 10.6 CONDITIONS FOR MAINTAINING THE ATTESTATION LETTER 10.7 MODIFICATIONS TO THE PRODUCT 10.8 RESPONSIBILITIES AND COMMITMENTS OF THE BNQ AND CLIENT 10.9 SUSPENSION OF THE ATTESTATION LETTER 10.10 WITHDRAWAL OF THE ATTESTATION LETTER 10.11 CLOSURE OF THE ATTESTATION FILE 10.12 HANDLING COMPLAINTS AND APPEALS 10.13 ATTESTED PRODUCTS FOUND TO BE HAZARDOUS 	8 8 9 9 TTER 9 10 10 10 11 12 13 13		
11	THE BNQ'S ATTESTATION LETTER AND MARK OF CONFORMITY			



12	LICENCE	TO USE THE BNQ'S ATTESTATION LETTER AND MARK OF CONFORMITY	18
		COPYRIGHT CLIENT'S USER RIGHTS AND OBLIGATIONS	18 19
ANNEX	ХА —	TEST METHOD — DETERMINATION OF FILTRATION EFFICIENCY OF A FILTERING FACEPIECE (FFP) FOR PARTICLES OF 20 nm TO 4000 nm	21
	FIGURE	A.1 — TEST BENCH DIAGRAM	29
ANNEX	ХВ—	SAMPLING OF MASKS	30
	TABLE B	.1 Sampling Table	30
ANNEX	C —	APPLICABLE TERMS AND CONDITIONS TO DETERMINE CONFORMITY OF A LOT	31
	TABLE C	.1 — DETERMINATION OF LOT CONFORMITY	31
	TABLE C	.2 — DETERMINATION OF LOT CONFORMITY	33
ANNEX	(D —	REQUIREMENTS CONCERNING THE QUALITY MANAGEMENT SYSTEM	34
ANNEX	ΣΕ—	INFORMATIVE REFERENCES	36
ANNEX F —		BIBLIOGRAPHY OF ANNEX A "TEST METHOD — DETERMINATION OF FILTRATION EFFICIENCY OF A FILTERING FACEPIECE (FFP) FOR PARTICLES OF 20 nm TO 4000 nm"	38
ANNEX	G	BIBLIOGRAPHY	39